TOSHIBA BIPOLAR DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TD62083AFN,TD62084AFN

8CH DARLINGTON SINK DRIVER

The TD62083AFN and TD62084AFN are high-voltage, high-current darlington drivers comprised of eight NPN darlington pairs.

All units feature integral clamp diodes for switching inductive loads.

Applications include relay, hammer, lamp and display (LED) drivers.

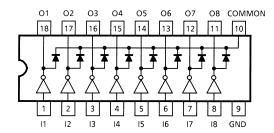
Please observe the thermal condition for using.

FEATURES

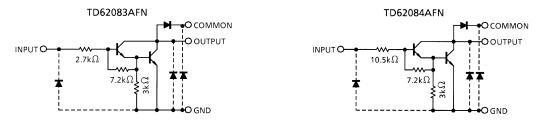
- Package Type : SSOP18 pin
- High Sustaining Voltage Output : 50 V (min)
- Output Current (Single Output) : 500 mA / ch (max)
- Output Clamp Diodes
- Inputs compatible with Various Types of Logic.

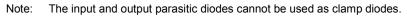
TYPE	INPUT BASE RESISTOR	DESIGNATION
TD62083AFN	2.7 kΩ	TTL, 5-V CMOS
TD62084AFN	10.5 kΩ	6~15-V P-MOS, CMOS

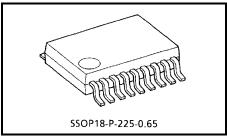
PIN CONNECTION (TOP VIEW)



SCHEMATICS (EACH DRIVER)







Weight: 0.09 g (typ.)

ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Output Sustaining Voltage	V _{CE (SUS)}	-0.5~50	V	
Output Current	IOUT	500	mA / ch	
Input Voltage	V _{IN}	-0.5~30	V	
Clamp Diode Reverse Voltage	V _R	50	V	
Clamp Diode Forward Current	١ _F	500	mA	
Power Dissipation	P _D (Note)	0.96	W	
Operating Temperature	T _{opr}	-40~85	°C	
Storage Temperature	T _{stg}	-55~150	°C	

Note: On Glass Epoxy PCB (50 × 50 × 1.6 mm Cu 40%)

RECOMMENDED OPERATING CONDITIONS (Ta = -40~85°C)

CHARACTERISTIC		SYMBOL	CONDITION		MIN	TYP.	MAX	UNIT
Output Sustaining Voltage		V _{CE (SUS)}			0	_	50	V
Output Current			DC 1 Circuit		-	—	350	
		I _{OUT} (Note)	T _{pw} = 25 ms, 8 Circuits Ta = 85°C, T _j = 120°C	Duty = 10%	0	_	260	mA / ch
				Duty = 50%	0	_	90	
Input Voltage		V _{IN}			0	_	30	V
Input Voltage	/oltage TD62083				2.5	_	30	v
(Output ON) TD62084		V _{IN(ON)}			8	_	30	v
Clamp Diode Reverse Voltage		V _R			_	_	50	V
Clamp Diode Forward Current		١ _F			_	_	400	mA
Power Dissipation		PD	Ta = 85°C (Note)			—	0.4	W

Note: On Glass Epoxy PCB (50 × 50 × 1.6 mm Cu 40%)

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

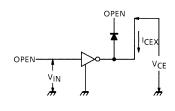
CHARACTER	ISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION		TEST CONDITION		TEST CONDITION		TEST CONDITION		MIN	TYP.	MAX	UNIT
Output Leakage Current	TD62083	ICEX	1	V _{CE} = 50 V	Ta = 25°C	_	—	50	μA						
	1202000			V _{CE} = 50 V	Ta = 85°C	—	—	100							
	TD62084			V _{CE} = 50 V	V _{IN} = 1 V	—	—	500							
				I _{OUT} = 350 mA, I _{IN} = 500 μA		—	1.3	1.6							
Output Saturation Voltage		V _{CE (sat)}	2	I _{OUT} = 200 mA, I _{IN} = 350 μA		-	1.1	1.3	V						
				I _{OUT} = 100 mA, I _{IN} = 250 μA		-	0.9	1.1							
	TD62083				V _{IN} = 3.85 V		0.93	1.35							
Input Current	TD62084	I _{IN (ON)}	3	V _{IN} = 5 V		-	0.35	0.5	mA						
	1002084			V _{IN} = 12 V		-	1.0	1.45							
		I _{IN (OFF)}	4	I _{OUT} = 500 μA, Ta = 85°C		50	65	_	μA						
Input Voltage	TD62083		5	V _{CE} = 2 V, I _{OUT} = 200 mA V _{CE} = 2 V, I _{OUT} = 250 mA V _{CE} = 2 V, I _{OUT} = 300 mA		-	_	2.4	V						
						_	_	2.7							
						_	_	3.0							
	TD62084	Vin (on)		V _{CE} = 2 V, I _{OUT} = 125 mA		_	_	5.0							
				V _{CE} = 2 V, I _{OUT} = 200 mA V _{CE} = 2 V, I _{OUT} = 275 mA		_	_	6.0							
						_	—	7.0							
				V _{CE} = 2 V, I _{OUT} = 350 mA		_	—	8.0							
DC Current Transfer Ratio		h _{FE}	2	V _{CE} = 2 V, I _{OUT} = 350 mA		1000	—	_							
Clamp Diode Reverse Current		۱ _R	6	Ta = 25°C V _R = 50 V		_	—	50							
				Ta = 85°C V	′ _R = 50 V	_	_	100	μA						
Clamp Diode Forward Voltage		VF	7	I _F = 350 mA		-	_	2.0	V						
Input Capacitance		C _{IN}	_			-	15	_	pF						
Turn-On Delay		t _{ON}	8	R _L = 125 Ω, V _{OUT} = 50 V R _L = 125 Ω, V _{OUT} = 50 V		_	0.1	_	μs						
Turn-Off Delay	Turn-Off Delay		ð			_	0.2	_							

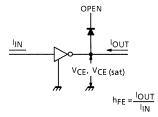
TEST CIRCUIT

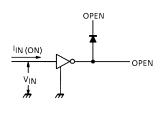
1. I_{CEX}

2. V_{CE (sat)}, h_{FE}

3. I_{IN (ON)}





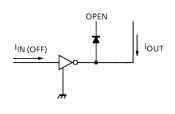


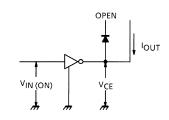
4. I_{IN (OFF)}

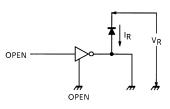
5. V_{IN (ON)}



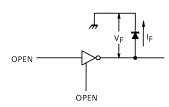




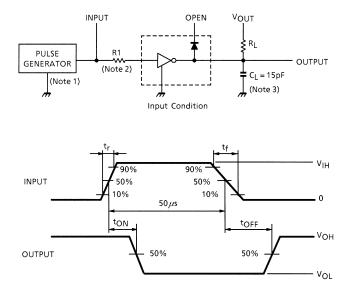




7. V_F



8. t_{ON} , t_{OFF}



- Note 1: Pulse Width 50 $\mu s,$ Duty Cycle 10% Output Impedance 50 $\Omega,$ t_{f} \leq 5ns, t_{f} \leq 10 ns
- Note 2: See below

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TYPE NUMBER	R1	V _{IH}
TD62083AFN	0	3 V
TD62084AFN	0	8 V

Note 3: CL includes probe and jig capacitance

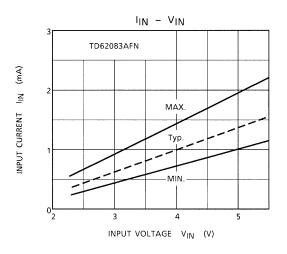
PRECAUTIONS for USING

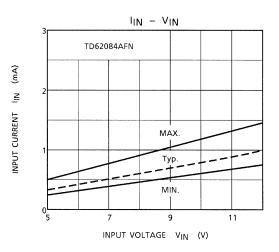
This IC does not include built-in protection circuits for excess current or overvoltage.

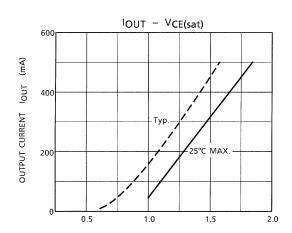
If this IC is subjected to excess current or overvoltage, it may be destroyed.

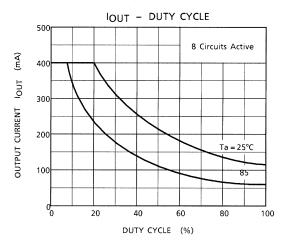
Hence, the utmost care must be taken when systems which incorporate this IC are designed.

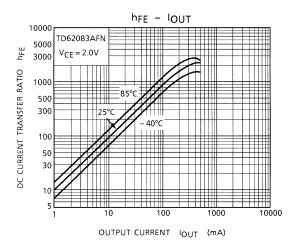
Utmost care is necessary in the design of the output line, COMMON and GND line since IC may be destroyed due to short-circuit between outputs, air contamination fault, or fault by improper grounding.

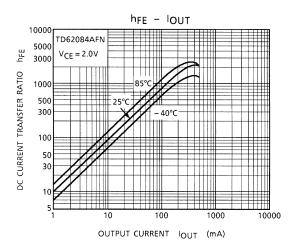


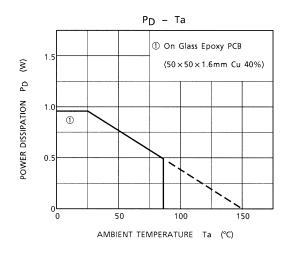








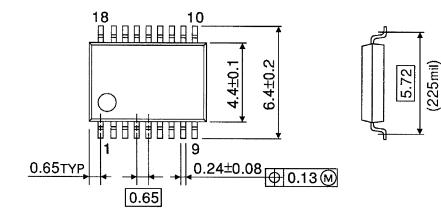


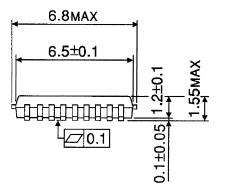


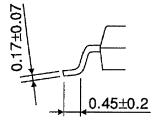
PACKAGE DIMENSIONS

SSOP18-P-225-0.65

Unit : mm







Weight: 0.09 g (typ.)

Notes on Contents

1. Equivalent Circuits

The equivalent circuit diagrams may be simplified or some parts of them may be omitted for explanatory purposes.

2. Test Circuits

Components in the test circuits are used only to obtain and confirm the device characteristics. These components and circuits are not guaranteed to prevent malfunction or failure from occurring in the application equipment.

IC Usage Considerations

Notes on Handling of ICs

- The absolute maximum ratings of a semiconductor device are a set of ratings that must not be exceeded, even for a moment. Do not exceed any of these ratings. Exceeding the rating(s) may cause the device breakdown, damage or deterioration, and may result injury by explosion or combustion.
- (2) Use an appropriate power supply fuse to ensure that a large current does not continuously flow in case of over current and/or IC failure. The IC will fully break down when used under conditions that exceed its absolute maximum ratings, when the wiring is routed improperly or when an abnormal pulse noise occurs from the wiring or load, causing a large current to continuously flow and the breakdown can lead smoke or ignition. To minimize the effects of the flow of a large current in case of breakdown, appropriate settings, such as fuse capacity, fusing time and insertion circuit location, are required.
- (3) If your design includes an inductive load such as a motor coil, incorporate a protection circuit into the design to prevent device malfunction or breakdown caused by the current resulting from the inrush current at power ON or the negative current resulting from the back electromotive force at power OFF. IC breakdown may cause injury, smoke or ignition. Use a stable power supply with ICs with built-in protection functions. If the power supply is unstable, the protection function may not operate, causing IC breakdown. IC breakdown may cause injury, smoke or ignition.
- (4) Do not insert devices in the wrong orientation or incorrectly. Make sure that the positive and negative terminals of power supplies are connected properly. Otherwise, the current or power consumption may exceed the absolute maximum rating, and exceeding the rating(s) may cause the device breakdown, damage or deterioration, and may result injury by explosion or combustion. In addition, do not use any device that is applied the current with inserting in the wrong orientation or incorrectly even just one time.
- (5) Carefully select external components (such as inputs and negative feedback capacitors) and load components (such as speakers), for example, power amp and regulator. If there is a large amount of leakage current such as input or negative feedback condenser, the IC output DC voltage will increase. If this output voltage is connected to a speaker with low input withstand voltage, overcurrent or IC failure can cause smoke or ignition. (The over current can cause smoke or ignition from the IC itself.) In particular, please pay attention when using a Bridge Tied Load (BTL) connection type IC that inputs output DC voltage to a speaker directly.

Points to Remember on Handling of ICs

(1) Heat Radiation Design

In using an IC with large current flow such as power amp, regulator or driver, please design the device so that heat is appropriately radiated, not to exceed the specified junction temperature (Tj) at any time and condition. These ICs generate heat even during normal use. An inadequate IC heat radiation design can lead to decrease in IC life, deterioration of IC characteristics or IC breakdown. In addition, please design the device taking into considerate the effect of IC heat radiation with peripheral components.

(2) Back-EMF

When a motor rotates in the reverse direction, stops or slows down abruptly, a current flow back to the motor's power supply due to the effect of back-EMF. If the current sink capability of the power supply is small, the device's motor power supply and output pins might be exposed to conditions beyond maximum ratings. To avoid this problem, take the effect of back-EMF into consideration in system design.

RESTRICTIONS ON PRODUCT USE

Handbook" etc. 021023 A

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document shall be made at the customer's own risk. 021023 B

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